

# **AUTOMOTIVE GRADE**

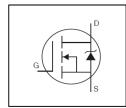
# AUIRL3705Z AUIRL3705ZS AUIRL3705ZL

# **Features**

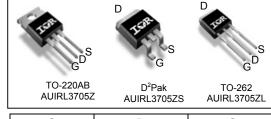
- Logic Level
- · Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- · Repetitive Avalanche Allowed up to Timax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*

# **Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



	ПЕЛГЕІ	Power MOSFET
V <sub>DSS</sub>		55V
R <sub>DS(on)</sub> typ.		$6.5 m\Omega$
max.		$8.0 {\sf m}\Omega$
D (Silicon Limited)		86A®
I <sub>D (Package Limited)</sub>		75A



G	D	S
Gate	Drain	Source

Boos part number	Dookogo Typo	Standard Pack		Orderable Part Number	
Base part number	Package Type	Form	Quantity	Orderable Part Number	
AUIRL3705Z	TO-220	Tube	50	AUIRL3705Z	
AUIRL3705ZL	TO-262	Tube	50	AUIRL3705ZL	
ALUDI 270570	D <sup>2</sup> -Pak	Tube	50	AUIRL3705ZS	
AUIRL3705ZS	DPak	Tape and Reel Left	800	AUIRL3705ZSTRL	

# Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	86®	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	61	1
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	75	A
I <sub>DM</sub>	Pulsed Drain Current ①	340	1
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	130	W
	Linear Derating Factor	0.88	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 16	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ②	120	ma I
E <sub>AS</sub> (tested)	Single Pulse Avalanche Energy Tested Value ®	180	- mJ
I <sub>AR</sub>	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy S		mJ
TJ	Operating Junction and	-55 to + 175	
$T_{STG}$	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

# **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case®		1.14	
$R_{\theta CS}$	Case-to-Sink, Flat, Greased Surface ⑦	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient ⑦		62	C/VV
$R_{\theta JA}$	Junction-to-Ambient ( PCB Mount, steady state) ®		40	

HEXFET® is a registered trademark of Infineon.

2015-10-29

<sup>\*</sup>Qualification standards can be found at www.infineon.com



# Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.055		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
			6.5	8.0		$V_{GS} = 10V, I_D = 52A$ ③
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			11	mΩ	$V_{GS} = 5.0V, I_D = 43A$ ③
- (- /				12		VGS = 4.5V, ID = 30A ③
$V_{GS(th)}$	Gate Threshold Voltage	1.0		3.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
gfs	Forward Trans conductance	150			S	$V_{DS} = 25V, I_{D} = 52A$
1	Drain-to-Source Leakage Current			20		$V_{DS} = 55V, V_{GS} = 0V$
DSS	Drain-to-Source Leakage Current			250	μΑ	$V_{DS} = 55V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
GSS	Gate-to-Source Forward Leakage			200	n ^	$V_{GS} = 16V$
	Gate-to-Source Reverse Leakage			-200	nA	V <sub>GS</sub> = -16V

# Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

ıct:
= 1.0MHz
= 1.0MHz
14V ④

# **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			75		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			340		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 52A, V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		16	24	ns	$T_J = 25^{\circ}C$ , $I_F = 43A$ , $V_{DD} = 28V$
$Q_{rr}$	Reverse Recovery Charge		7.4	11	nC	di/dt = 100A/µs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsi	ic turn-c	on time	is neglio	gible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig.11)
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25$ °C, L = 0.09mH,  $R_G = 25\Omega$ ,  $I_{AS} = 52$ A,  $V_{GS} = 10$ V. Part not recommended for use above this value.
- $\oplus$  C<sub>oss</sub> eff. is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- © Limited by T<sub>Jmax</sub>, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- © This value determined from sample failure population 100% tested to this value in production.
- This is only applied to TO-220AB package.
- This is applied to D<sup>2</sup> Pak, When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- R<sub>θ</sub> is measured at T<sub>L</sub> of approximately 90°C
- © Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 75A. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements.



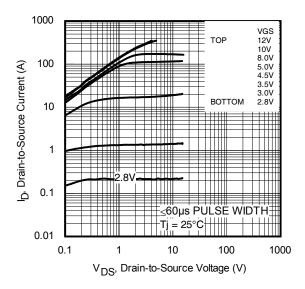


Fig. 1 Typical Output Characteristics

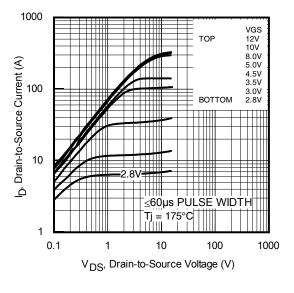


Fig. 2 Typical Output Characteristics

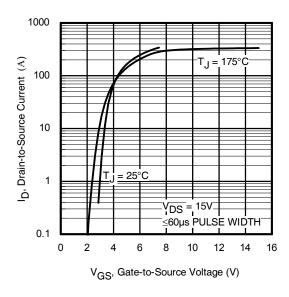


Fig. 3 Typical Transfer Characteristics

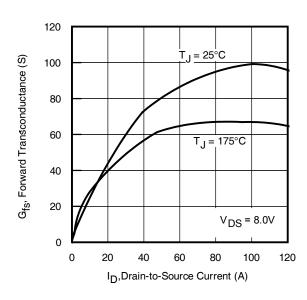


Fig. 4 Typical Forward Transconductance vs. Drain Current



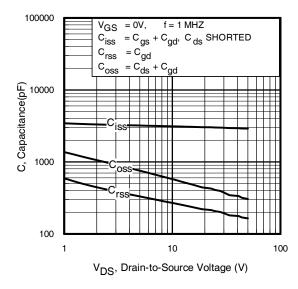


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

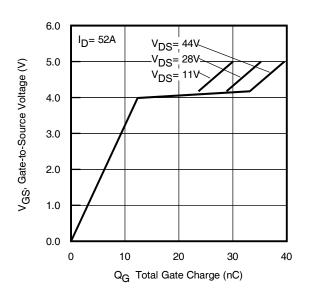
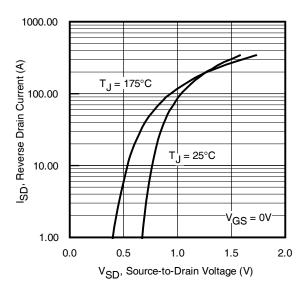


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage



**Fig. 7** Typical Source-to-Drain Diode Forward Voltage

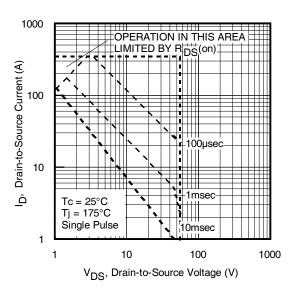
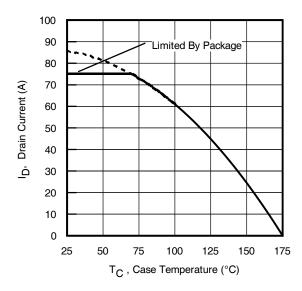
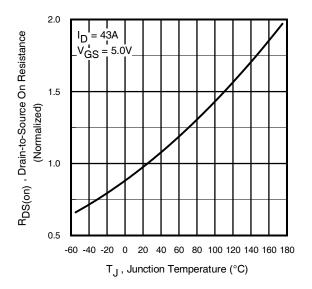


Fig 8. Maximum Safe Operating Area





**Fig 9.** Maximum Drain Current vs. Case Temperature



**Fig 10.** Normalized On-Resistance vs. Temperature

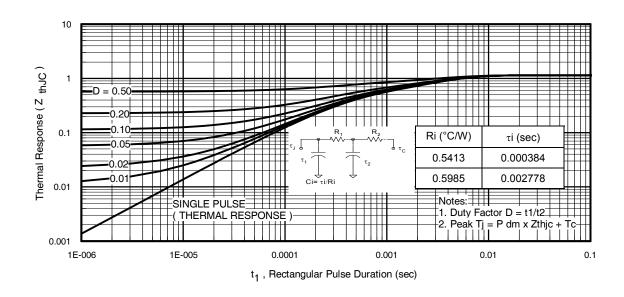


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



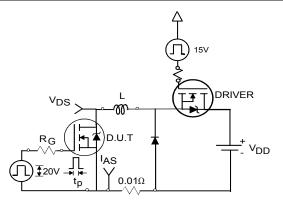


Fig 12a. Unclamped Inductive Test Circuit

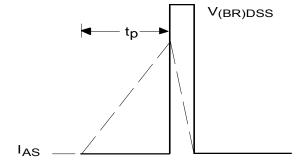


Fig 12b. Unclamped Inductive Waveforms

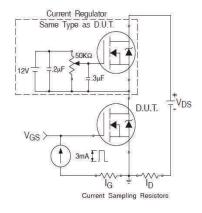


Fig 13a. Gate Charge Test Circuit

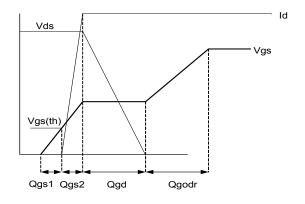


Fig 13b. Gate Charge Waveform

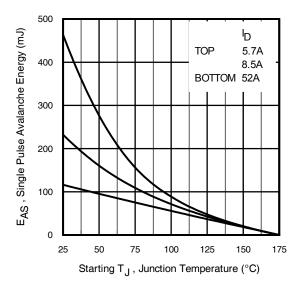


Fig 12c. Maximum Avalanche Energy vs. Drain Current

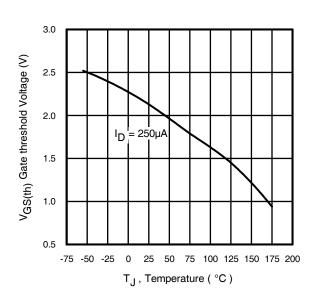


Fig 14. Threshold Voltage vs. Temperature



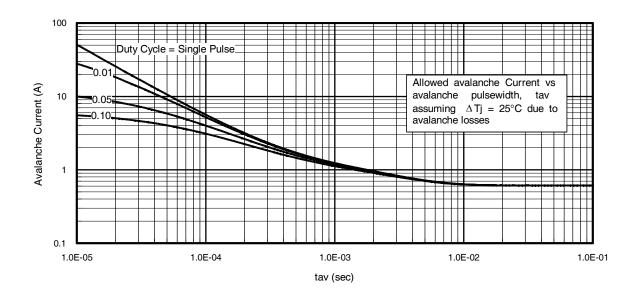
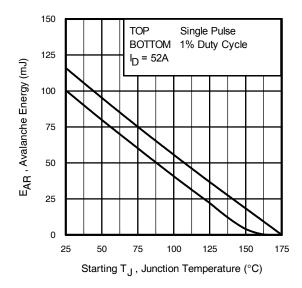


Fig 15. Avalanche Current vs. Pulse width



# Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T<sub>jmax</sub> is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- ΔT = Allowable rise in junction temperature, not to exceed T<sub>jmax</sub> (assumed as 25°C in Figure 14, 15).

tav = Average time in avalanche.

D = Duty cycle in avalanche =  $t_{av} \cdot f$ 

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

Fig 16. Maximum Avalanche Energy vs. Temperature



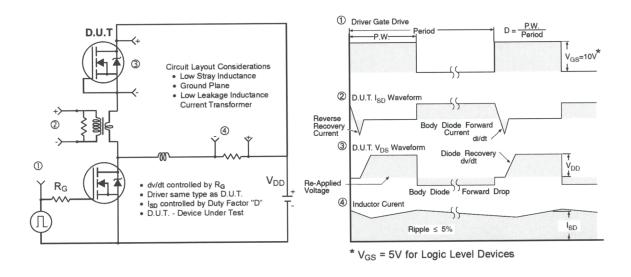


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

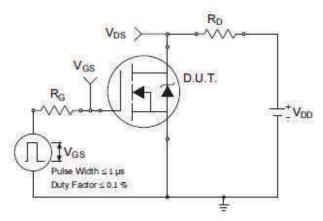


Fig 18a. Switching Time Test Circuit

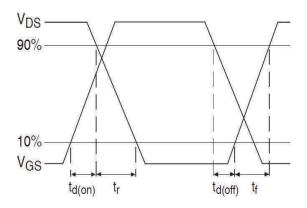
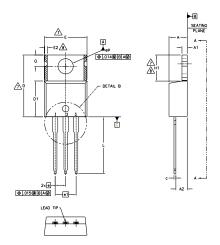
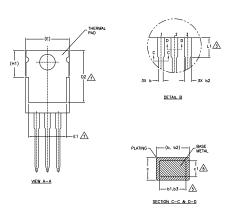


Fig 18b. Switching Time Waveforms



# TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





### NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
- DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
- LEAD DIMENSION AND FINISH UNCONTROLLED IN L1
- DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3.56	4.83	.140	.190	
A1	1,14	1.40	.045	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
ь1	0.38	0.97	.015	.038	5
b2	1,14	1.78	.045	.070	
b3	1,14	1.73	.045	.068	5
С	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	_	.030	8
е	2.54	2.54 BSC .100 BSC 5.08 BSC .200 BSC		BSC BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
ØΡ	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

### LEAD ASSIGNMENTS

### HEXFET

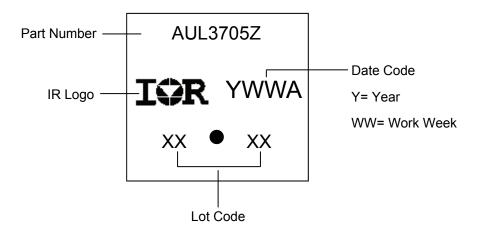
- 1.- GATE 2.- DRAIN 3.- SOURCE

1.- GATE 2.- COLLECTOR 3.- EMITTER

# DIODES

- 1.- ANODE
- 2.- CATHODE 3.- ANODE

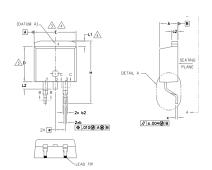
# **TO-220AB Part Marking Information**

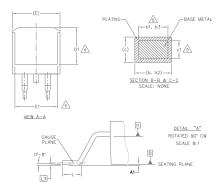


Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>



# D<sup>2</sup>Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





M	Λ	Т	F	S	

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S	DIMENSIONS					
M B	MILLIM	ETERS	INC	HES	O T E S	
O L	MIN.	MAX.	MIN.	MAX.	E S	
А	4.06	4.83	.160	.190		
A1	0.00	0.254	.000	.010		
Ь	0.51	0.99	.020	.039		
ь1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
ь3	1.14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
с1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	_	.270	_	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	_	.245	_	4	
е	2.54	BSC	.100	.100 BSC		
Н	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	_	1.68	_	.066	4	
L2	_	1.78	_	.070		
L3	0.25	BSC	.010	BSC		

### LEAD ASSIGNMENTS

### DIODES

1.— ANODE (TWO DIE) / OPEN (ONE DIE) 2, 4.— CATHODE 3.— ANODE

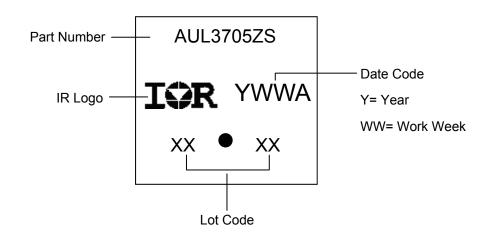
## HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

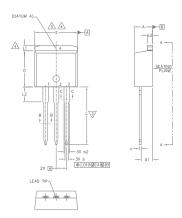
# D<sup>2</sup>Pak (TO-263AB) Part Marking Information

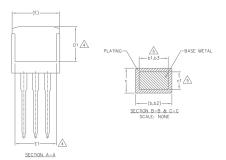


Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>



# TO-262 Package Outline (Dimensions are shown in millimeters (inches)





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED O.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

### LEAD ASSIGNMENTS

### IGBTs, CoPACK

- 1.- GATE
  2.- COLLECTOR
  3.- EMITTER
  4.- COLLECTOR

### HEXFET DIODES

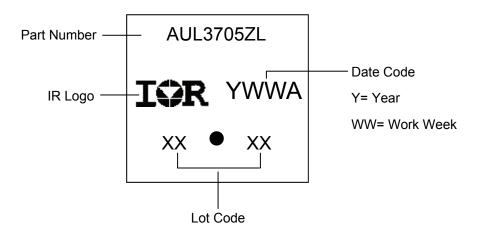
1.- ANODE (TWO DIE) / OPEN (ONE DIE) 1.- GATE

2.- DRAIN 3.- SOURCE 2, 4.- CATHODE 3.- ANODE

4.- DRAIN

S Y M		DIMENSIONS					
В	MILLIM	ETERS	INC	HES	O T E S		
0 L	MIN.	MAX.	MIN.	MAX.	S E		
А	4.06	4.83	.160	.190			
A1	2.03	3.02	.080	.119			
b	0.51	0.99	.020	.039			
b1	0.51	0.89	.020	.035	5		
b2	1.14	1.78	.045	.070			
ь3	1.14	1.73	.045	.068	5		
С	0.38	0.74	.015	.029			
c1	0.38	0.58	.015	.023	5		
c2	1.14	1.65	.045	.065			
D	8.38	9.65	.330	.380	3		
D1	6.86	-	.270	_	4		
E	9.65	10.67	.380	.420	3,4		
E1	6.22	_	.245		4		
е	2.54	BSC	.100	BSC			
L	13.46	14.10	.530	.555			
L1	_	1.65	_	.065	4		
L2	3.56	3.71	.140	.146			

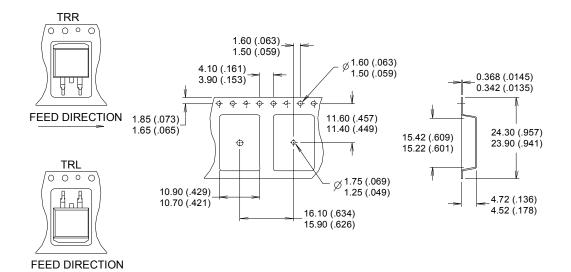
# **TO-262 Part Marking Information**

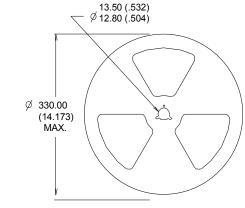


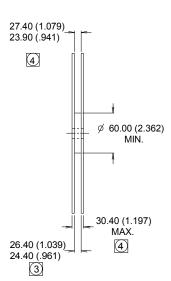
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



# D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







NOTES:

- 1. COMFORMS TO EIA-418.
- 2. CONTROLLING DIMENSION: MILLIMETER.
- 🗷 DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



### Qualification Information

		Automotive (per AEC-Q101)	
			is part number(s) passed Automotive qualification. Infineon's consumer qualification level is granted by extension of the higher el.
Moisture Sensitivity Level		TO-220 Pak	N/A
		D <sup>2</sup> -Pak	MSL1
		TO-262	
ESD	Machine Model	Class M4 (+/- 425V) <sup>†</sup>	
		AEC-Q101-002	
	Human Body Model	Class H1C (+/- 2000V) <sup>†</sup>	
		AEC-Q101-001	
	Charged Device Model	Class C5 (+/- 1125V) <sup>†</sup>	
		AEC-Q101-005	
RoHS Compliant		Yes	

# **Revision History**

Date	Comments		
10/29/2015	Updated datasheet with corporate template		
10/29/2013	Corrected ordering table on page 1.		

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